

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/624,489	VIERICH ET AL.	
Examiner	Art Unit	
Shew-Fen Lin	2166	

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	1-10	8/7/2006	SFL
707	102	8/7/2006	SFL
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (US-PUB, USPAT, USOCR, EPO, JPO, IBM-TDB)	8/7/2006	SFL		
consult with Khanh Pham	8/7/2006	SFL		
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